

<b>Notice of References Cited</b>	Application/Control No. 10/712,246	Applicant(s)/Patent Under Reexamination YU ET AL.	
	Examiner Thuy V. Tran	Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0155853 A1	08-2004	Lin, Yung-Lin	345/102
	B	US-2004/0061708 A1	04-2004	Oh, Jang Geun	345/690
	C	US-2003/0151601 A1	08-2003	Chung et al.	345/211
	D	US-6,762,742	07-2004	Moon et al.	345/102
	E	US-6,396,217	05-2002	Weindorf, Paul Fredrick Luther	315/169.1
	F	US-5,786,801	07-1998	Ichise, Atsushi	345/102
	G	US-5,272,327	12-1993	Mitchell et al.	250/205
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.